

# RELIABILITY MONITOR

PROCESS: 0.8  $\mu$ m Double Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153	A7	JUN '98	P22294	9740	ANAM-KOREA (AICL)	DN725561AAB	44 PIN PLCC	48	237	0
DS2153Q	A7	MAR '98	P22292	9734	ANAM-KOREA (AICL)	DN720030AAB	44 PIN PLCC	48	237	0

TOTALS FOR:           0.8  $\mu$ m Double Poly, Single Metal           FAIL RATE (Fits): 314   DEVICE HRS: 2.92E+06   0

# RELIABILITY MONITOR

PROCESS: 0.8  $\mu$ m Single Poly, Double Metal

## STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	C1	DEC '97	P21627	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	48	232	0
DS1302	C1	MAR '98	P21826	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	48	229	0
DS1315	B1	MAR '98	P21737	9803	ANAM-PI (AAPI)	DK740539AAA	16 PIN PDIP	48	234	0
DS17485	A2	FEB.'98	P22032	9730	ANAM-KOREA (AICL)	DN713701AAE	24 PIN SOIC	48	230	0
DS17485	A2	MAY '98	P22308	9814	ANAM-KOREA (AICL)	DN803023AAD	24 PIN SOIC	48	230	0

## STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	C1	DEC '97	P21731	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	336	77	0
DS1302	C1	DEC '97	P21731	9745	ANAM-KOREA (AICL)	DN736077AAC	8 PIN SOIC	1000	77	0
DS1302	C1	MAR '98	P21972	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	336	75	0
DS1302	C1	MAR '98	P21972	9808	HYUNDAI-KOREA (HEI)	DL750312ABA	8 PIN SOIC	1000	75	0
DS1315	B1	MAR '98	P21792	9803	ANAM-PI (AAPI)	DK740539AAA	16 PIN PDIP	336	65	0
DS1315	B1	MAR '98	P21792	9803	ANAM-PI (AAPI)	DK740539AAA	16 PIN PDIP	1000	65	0

TOTALS FOR: 0.8  $\mu$ m Single Poly, Double Metal      FAIL RATE (Fits): 16      DEVICE HRS: 5.62E+07      0

# RELIABILITY MONITOR

PROCESS: 0.8 µm Single Poly, Single Metal

## STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	JUN '98	P22198	9741	ALPHTK-BANGKOK	DJ723284AAF	8PN SOIC, 208MIL	48	237	0
DS1621	A5	JUN '98	P22200	9745	CARSEM	DM734572AA	8 PIN SOIC	48	237	0
DS1621	A5	DEC '97	P21367	9740	CARSEM	DM727709AA	8 PIN SOIC	48	236	0
DS21S07	E	MAY '98	P22171	9815	CARSEM	DM805323AA	20 PIN TSSOP	48	234	0
DS21S07	E	FEB '98	P21637	9802	CARSEM	DM741735AB	20 PIN TSSOP	48	234	0
DS2401	B2	MAR '98	P22152	9802	CARSEM	DM741755AC	T0-92	48	234	0
DS2401	B2	JUN '98	P22123	9805	CARSEM	DM743297AD	T0-92	48	234	0
DS2502	B4	JUN '98	P22251	9814	CARSEM	DM751356AFA	8 PIN SOIC	48	193	0
DS80320	B5	JAN '98	P21300	9749	ANAM-PI (AAPI)	DK739467AAA	40 PIN PDIP	48	234	0
DS80320	B5	APR '98	P21893	9810	ANAM-PI (AAPI)	DK748103AAB	40 PIN PDIP	48	234	0

## STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1621	A5	DEC '97	P21727	9740	CARSEM	DM727709AA	8 PIN SOIC	336	77	0
DS1621	A5	DEC '97	P21727	9740	CARSEM	DM727709AA	8 PIN SOIC	1000	77	0
DS21S07	E	FEB '98	P21694	9802	CARSEM	DM741735AB	20 PIN TSSOP	336	77	0
DS21S07	E	MAY '98	P22242	9815	CARSEM	DM805323AA	20 PIN TSSOP	336	77	0
DS21S07	E	FEB '98	P21694	9802	CARSEM	DM741735AB	20 PIN TSSOP	1000	77	0
DS21S07	E	MAY '98	P22242	9815	CARSEM	DM805323AA	20 PIN TSSOP	1000	77	0

## RELIABILITY MONITOR

DS2401	B2	MAR '98	P22162	9802	CARSEM	DM741755AC	T0-92	336	77	0
DS2401	B2	JUN '98	P22157	9805	CARSEM	DM743297AD	T0-92	336	77	0
DS2401	B2	MAR '98	P22162	9802	CARSEM	DM741755AC	T0-92	1000	77	0
DS2401	B2	JUN '98	P22157	9805	CARSEM	DM743297AD	T0-92	1000	77	0
DS80320	B5	JAN '98	P21353	9749	ANAM-PI (AAPI)	DK739467AAA	40 PIN PDIP	336	77	0
DS80320	B5	APR '98	P21964	9810	ANAM-PI (AAPI)	DK748103AAB	40 PIN PDIP	336	77	0
DS80320	B5	APR '98	P21964	9810	ANAM-PI (AAPI)	DK748103AAB	40 PIN PDIP	1000	77	0
DS80320	B5	JAN '98	P21353	9749	ANAM-PI (AAPI)	DK739467AAA	40 PIN PDIP	1000	77	0

TOTALS FOR:      0.8 µm Single Poly, Single Metal      FAIL RATE (Fits):      4      DEVICE HRS: 2.27E+08      0

# RELIABILITY MONITOR

PROCESS: 1.2 µm Single Poly, Single Metal

## STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1000	E3	FEB '98	P21467	9750	OMEDATA	DD740614ABA	8 PIN PDIP	48	234	0
DS1233	A5	APR '98	P22075	9752	CARSEM	DM740622AC	SOT-223	48	229	0
DS1233	A5	JAN '98	P21396	9737	CARSEM	DM721164AB	SOT-223	48	229	0
DS1267	A1	NOV.'97	P20991	9737	ANAM-PI (AAPI)	DK727730AAA	20 PIN TSSOP	48	234	0
DS1620	C1	MAR '98	P22173	9746	ALPHTK-BANGKOK	DJ723286AAC	8PN SOIC, 208MIL	48	232	0
DS1620	C1	DEC '97	P21529	9740	ALPHTK-BANGKOK	DJ724413AAD	8PN SOIC, 208MIL	48	237	0
DS1669	B3	NOV.'97	P21187	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	48	38	0
DS1669	B3	NOV.'97	P21187	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	48	232	0
DS5002	B3	APR 98 '	P22249	9806	CARSEM	DM743264AA	80 PIN PQFP	48	199	0

## STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1000	E3	FEB '98	P21488	9750	OMEDATA	DD740614ABA	8 PIN PDIP	336	77	0
DS1000	E3	FEB '98	P21488	9750	OMEDATA	DD740614ABA	8 PIN PDIP	1000	77	0
DS1233	A5	JAN '98	P21440	9737	CARSEM	DM721164AB	SOT-223	336	77	0
DS1233	A5	APR '98	P22185	9752	CARSEM	DM740622AC	SOT-223	336	77	0
DS1233	A5	APR '98	P22185	9752	CARSEM	DM740622AC	SOT-223	1000	77	0
DS1233	A5	JAN '98	P21440	9737	CARSEM	DM721164AB	SOT-223	1000	77	0
DS1267	A1	NOV.'97	P21102	9737	ANAM-PI (AAPI)	DK727730AAA	20 PIN TSSOP	336	77	0

## RELIABILITY MONITOR

DS1267	A1	NOV.'97	P21102	9737	ANAM-PI (AAPI)	DK727730AAA	20 PIN TSSOP	1000	77	0
DS1620	C1	DEC '97	P21852	9740	ALPHTK-BANGKOK	DJ724413AAD	8PN SOIC, 208MIL	336	77	0
DS1620	C1	DEC '97	P21852	9740	ALPHTK-BANGKOK	DJ724413AAD	8PN SOIC, 208MIL	1000	77	0
DS1669	B3	NOV.'97	P21819	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	336	77	0
DS1669	B3	NOV.'97	P21819	9744	OMEDATA	DD650016AAA	8PN SOIC, 208MIL	1000	76	0

TOTALS FOR:      1.2  $\mu$ m Single Poly, Single Metal      FAIL RATE (Fits):      5      DEVICE HRS: 1.72E+08      0

# RELIABILITY MONITOR

PROCESS: 2.0 µm Single Poly, Single Metal

## STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JAN '98	P21487	9745	ANAM-KOREA (AICL)	DN736121AAE	16 PIN SOIC	48	234	0
DS2180A	B3	MAY '98	P22196	9810	ANAM-KOREA (AICL)	DN752567AAB	44 PIN PLCC	48	236	0
DS2180A	B3	NOV.'97	P20995	9734	ANAM-KOREA (AICL)	DN725581AAC	44 PIN PLCC	48	235	0
DS2181A	A2	FEB.'98	P21699	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	48	237	0

## STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175S	D1	JAN '98	P21612	9745	ANAM-KOREA (AICL)	DN736121AAE	16 PIN SOIC	336	77	0
DS2175S	D1	JAN '98	P21612	9745	ANAM-KOREA (AICL)	DN736121AAE	16 PIN SOIC	1000	77	0
DS2180A	B3	NOV.'97	P21121	9734	ANAM-KOREA (AICL)	DN725581AAC	44 PIN PLCC	336	77	0
DS2180A	B3	NOV.'97	P21121	9734	ANAM-KOREA (AICL)	DN725581AAC	44 PIN PLCC	1000	77	0
DS2181A	A2	FEB.'98	P21777	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	336	77	0
DS2181A	A2	FEB.'98	P21777	9741	ANAM-KOREA (AICL)	DN728030AAB	44 PIN PLCC	1000	77	0

TOTALS FOR: 2.0 µm Single Poly, Single Metal FAIL RATE (Fits): 9 DEVICE HRS: 9.65E+07 0

# RELIABILITY MONITOR

PROCESS: 3.0 µm Single Poly, Single Metal

## STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210	C1	APR '98	P22232	9811	ANAM-KOREA (AICL)	DN752523AAC	16 PIN SOIC	48	233	0
DS1210	C1	JAN '98	P21776	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	48	234	0
DS1232	C1	APR '98	P22047	9805	ANAM-KOREA (AICL)	DN737280ABA	16 PIN SOIC	48	234	0
DS1232	C1	JAN '98	P21326	9740	HYUNDAI-KOREA (HEI)	DL728793AAF	16 PIN SOIC	48	234	0

## STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1210	C1	APR '98	P22262	9811	ANAM-KOREA (AICL)	DN752523AAC	16 PIN SOIC	336	77	0
DS1210	C1	APR '98	P22262	9811	ANAM-KOREA (AICL)	DN752523AAC	16 PIN SOIC	1000	77	0
DS1210	C1	JAN '98	P22233	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	336	77	0
DS1210	C1	JAN '98	P22233	9750	HYUNDAI-KOREA (HEI)	DN738347AAA	16 PIN SOIC	1000	77	0
DS1232	C1	APR '98	P22145	9805	ANAM-KOREA (AICL)	DN737280ABA	16 PIN SOIC	336	77	0
DS1232	C1	APR '98	P22145	9805	ANAM-KOREA (AICL)	DN737280ABA	16 PIN SOIC	1000	77	0
DS1232	C1	JAN '98	P21403	9740	HYUNDAI-KOREA (HEI)	DL728793AAF	16 PIN SOIC	336	77	0
DS1232	C1	JAN '98	P21403	9740	HYUNDAI-KOREA (HEI)	DL728793AAF	16 PIN SOIC	1000	77	0

TOTALS FOR: 3.0 µm Single Poly, Single Metal FAIL RATE (Fits): 7 DEVICE HRS: 1.23E+08 0

# RELIABILITY MONITOR

PROCESS: 5.0 µm Single Poly, Single Metal

## STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	MAY '98	P22138	9741	ANAM-KOREA (AICL)	DN729121ABA	24 PIN SOIC	48	234	0
DS2108	B1	FEB.'98	P21556	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	48	234	0
DS232	B3	JUN '98	P22122	9809	OMEDATA	DD747723ABD	16 PIN PDIP	48	234	0
DS232	B3	MAR '98	P21726	9809	OMEDATA	DD747723AAB	16 PIN PDIP	48	234	0

## STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2108	B1	MAY '98	P22153	9741	ANAM-KOREA (AICL)	DN729121ABA	24 PIN SOIC	336	77	0
DS2108	B1	FEB.'98	P21690	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	336	77	0
DS2108	B1	MAY '98	P22153	9741	ANAM-KOREA (AICL)	DN729121ABA	24 PIN SOIC	1000	77	0
DS2108	B1	FEB.'98	P21690	9740	ANAM-KOREA (AICL)	DN729120AAC	24 PIN SOIC	1000	77	0
DS232	B3	MAR '98	P21751	9809	OMEDATA	DD747723AAB	16 PIN PDIP	336	77	0
DS232	B3	MAR '98	P21751	9809	OMEDATA	DD747723AAB	16 PIN PDIP	1000	77	0

TOTALS FOR: 5.0 µm Single Poly, Single Metal      FAIL RATE (Fits): 15      DEVICE HRS: 5.99E+07      0